

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NOZAWA ET AL.	
		10/667,823	Examiner	Art Unit
Rodney G. McDonald		1753	Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,428,663	08-2002	Mostovoy et al.	204/298.12
	C	US-6,162,297	12-2000	Mintz et al.	118/715
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.